

# Marie-Paule Besland

## List of Publications by Year in descending order

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61  
papers

1,145  
citations

394421

19  
h-index

434195

31  
g-index

61  
all docs

61  
docs citations

61  
times ranked

1660  
citing authors

#	ARTICLE	IF	CITATIONS
1	A Leakyâ€“Integrateâ€“andâ€“Fire Neuron Analog Realized with a Mott Insulator. <i>Advanced Functional Materials</i> , 2017, 27, 1604740.	14.9	186
2	Resistive Switching in Mott Insulators and Correlated Systems. <i>Advanced Functional Materials</i> , 2015, 25, 6287-6305.	14.9	130
3	Reactive ion etching of solâ€“gel-processed SnO <sub>2</sub> transparent conducting oxide as a new material for organic light emitting diodes. <i>Synthetic Metals</i> , 2002, 127, 207-211.	3.9	42
4	TEM and XPS studies on CdS/CIGS interfaces. <i>Journal of Physics and Chemistry of Solids</i> , 2014, 75, 1279-1283.	4.0	41
5	Preparation and characterization of ZnS/CdS bi-layer for CdTe solar cell application. <i>Journal of Physics and Chemistry of Solids</i> , 2013, 74, 1879-1883.	4.0	39
6	Evidence for a new passivating indium rich phosphate prepared by ultraviolet/ozone oxidation of InP. <i>Applied Physics Letters</i> , 1991, 59, 1617-1619.	3.3	36
7	Electrical characterization of metal-oxide-InP tunnel diodes based on current-voltage, admittance and low frequency noise measurements. <i>Solid-State Electronics</i> , 1995, 38, 1035-1043.	1.4	36
8	Effect of RF sputtering power and vacuum annealing on the properties of AZO thin films prepared from ceramic target in confocal configuration. <i>Materials Science in Semiconductor Processing</i> , 2020, 118, 105217.	4.0	36
9	Different threshold and bipolar resistive switching mechanisms in reactively sputtered amorphous undoped and Cr-doped vanadium oxide thin films. <i>Journal of Applied Physics</i> , 2018, 123, .	2.5	33
10	Comparison of lanthanum substituted bismuth titanate (BLT) thin films deposited by sputtering and pulsed laser deposition. <i>Thin Solid Films</i> , 2006, 495, 86-91.	1.8	31
11	Passivation of InP using In(PO <sub>3</sub> ) <sub>3</sub> â€“condensed phosphates: From oxide growth properties to metalâ€“insulatorâ€“semiconductor fieldâ€“effectâ€“transistor devices. <i>Journal of Applied Physics</i> , 1992, 71, 2981-2992.	2.5	30
12	Electrical and optical characteristics of indium tin oxide thin films deposited by cathodic sputtering for top emitting organic electroluminescent devices. <i>Materials Science and Engineering C</i> , 2002, 21, 265-271.	7.3	26
13	Deposition of AlN films by reactive sputtering: Effect of radiofrequency substrate bias. <i>Thin Solid Films</i> , 2007, 515, 7105-7108.	1.8	25
14	Mott insulators: A large class of materials for Leaky Integrate and Fire (LIF) artificial neuron. <i>Journal of Applied Physics</i> , 2018, 124, .	2.5	24
15	First evidence of resistive switching in polycrystalline GaV <sub>4</sub> S <sub>8</sub> thin layers. <i>Physica Status Solidi - Rapid Research Letters</i> , 2011, 5, 53-55.	2.4	23
16	Raman and XPS studies of CIGS/Mo interfaces under various annealing temperatures. <i>Materials Letters</i> , 2014, 136, 278-281.	2.6	23
17	Investigation of copper indium gallium selenide material growth by selenization of metallic precursors. <i>Journal of Crystal Growth</i> , 2013, 382, 56-60.	1.5	21
18	Impact of the Cu-based substrates and catalyst deposition techniques on carbon nanotube growth at low temperature by PECVD. <i>Microelectronic Engineering</i> , 2007, 84, 2501-2505.	2.4	20

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19	Examination of the electrochemical reactivity of screen printed carbon electrode treated by radio-frequency argon plasma. <i>Electrochemistry Communications</i> , 2007, 9, 1798-1804.	4.7	19
20	Electrical characterizations of resistive random access memory devices based on GaV4S8 thin layers. <i>Thin Solid Films</i> , 2013, 533, 61-65.	1.8	19
21	Control of resistive switching in AM <sub>4</sub> Q <sub>8</sub> narrow gap Mott insulators: A first step towards neuromorphic applications. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2015, 212, 239-244.	1.8	18
22	Metal-insulator transitions in (V <sub>1-x</sub> Cr <sub>x</sub> ) <sub>2</sub> O <sub>3</sub> thin films deposited by reactive direct current magnetron co-sputtering. <i>Thin Solid Films</i> , 2016, 617, 56-62.	1.8	17
23	In Situ Studies of the Anodic Oxidation of Indium Phosphide. <i>Journal of the Electrochemical Society</i> , 1993, 140, 104-108.	2.9	15
24	Investigation of oxide layer on CdTe film surface and its effect on the device performance. <i>Materials Science in Semiconductor Processing</i> , 2015, 40, 402-406.	4.0	14
25	Studies of CdS/CdTe interface: Comparison of CdS films deposited by close space sublimation and chemical bath deposition techniques. <i>Thin Solid Films</i> , 2015, 582, 290-294.	1.8	13
26	Long-term stability of InP MIS devices. <i>Applied Surface Science</i> , 1991, 50, 383-389.	6.1	12
27	Desorption of ultraviolet-ozone oxides from InP under phosphorus and arsenic overpressures. <i>Journal of Applied Physics</i> , 1995, 77, 5167-5172.	2.5	12
28	Residual stress control in MoCr thin films deposited by ionized magnetron sputtering. <i>Surface and Coatings Technology</i> , 2006, 200, 6549-6553.	4.8	12
29	Magnetron Sputtering of Aluminium Nitride Thin Films for Thermal Management. <i>Plasma Processes and Polymers</i> , 2007, 4, S1-S5.	3.0	12
30	First demonstration of Leaky Integrate and Fire-artificial neuron behavior on (V <sub>0.95</sub> Cr <sub>0.05</sub> ) <sub>2</sub> O <sub>3</sub> thin film. <i>MRS Communications</i> , 2018, 8, 835-841.	1.8	11
31	Optimized SiO <sub>2</sub> /InP structures prepared by electron cyclotron resonance plasma. <i>Journal of Applied Physics</i> , 1996, 80, 3100-3109.	2.5	10
32	Screen-printed carbon electrode modified on its surface with amorphous carbon nitride thin film: Electrochemical and morphological study. <i>Electrochimica Acta</i> , 2007, 52, 5053-5061.	5.2	10
33	Electric Pulse Induced Resistive Switching in the Narrow Gap Mott Insulator GaMo <sub>4</sub> S <sub>8</sub> . <i>Key Engineering Materials</i> , 2014, 617, 135-140.	0.4	10
34	Surface evolution of sputtered Cu(In,Ga)Se <sub>2</sub> thin films under various annealing temperatures. <i>Journal of Materials Science: Materials in Electronics</i> , 2015, 26, 4840-4847.	2.2	10
35	<title>Strength of indium-phosphide-based microstructures</title>., 1997, 3008, 251.		9
36	Deposition by radio frequency magnetron sputtering of GaV4S8 thin films for resistive random access memory application. <i>Thin Solid Films</i> , 2013, 533, 54-60.	1.8	9

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37	Non-volatile resistive switching in the Mott insulator $(V_{1-x}Cr_x)_2O_3$ . <i>Physica B: Condensed Matter</i> , 2018, 536, 327-330.	2.7	9
38	Characterizations of CN <sub>x</sub> thin films made by ionized physical vapor deposition. <i>Thin Solid Films</i> , 2005, 482, 192-196.	1.8	8
39	Influence of Ion Bombardment and Annealing on the Structural and Optical Properties of TiO <sub>2</sub> Thin Films Deposited in Inductively Coupled TTIP/O <sub>2</sub> Plasma. <i>Plasma Processes and Polymers</i> , 2009, 6, S741.	3.0	8
40	Investigation of BST thin films deposited by RF magnetron sputtering in pure Argon. <i>Thin Solid Films</i> , 2010, 518, 4619-4622.	1.8	8
41	An optimized In <sub>0.4</sub> Cu <sub>0.6</sub> metallic precursors for chalcopyrite thin films. <i>Thin Solid Films</i> , 2013, 545, 251-256.	1.8	8
42	Structural and dielectric characterization of sputtered Tantalum Titanium Oxide thin films for high temperature capacitor applications. <i>Thin Solid Films</i> , 2016, 606, 127-132.	1.8	8
43	2 [micro sign]m resonant cavity enhanced InP/InGaAs single quantum well photo-detector. <i>Electronics Letters</i> , 1999, 35, 1272.	1.0	7
44	A study of different selenium sources in the synthesis processes of chalcopyrite semiconductors. <i>Vacuum</i> , 2014, 105, 46-51.	3.5	7
45	Competition between V <sub>2</sub> O <sub>3</sub> phases deposited by one-step reactive sputtering process on polycrystalline conducting electrode. <i>Thin Solid Films</i> , 2020, 705, 138063.	1.8	7
46	Low temperature plasma carbon nanotubes growth on patterned catalyst. <i>Microelectronic Engineering</i> , 2006, 83, 2427-2431.	2.4	6
47	Correlations Between the Electrical Characteristics of Metal <sup>100</sup> â€œOxide <sup>100</sup> â€œInP Tunnel Diodes and the Nature of Thin Interfacial Oxides. <i>Journal of the Electrochemical Society</i> , 1995, 142, 1343-1348.	2.9	5
48	In Situ Photoluminescence Control during Fabrication of SiO <sub>2</sub> /InP Structures. <i>Journal of the Electrochemical Society</i> , 1997, 144, 2086-2095.	2.9	5
49	Dip-coated La <sub>2</sub> Ti <sub>2</sub> O <sub>7</sub> as a buffer layer for growth of Bi <sub>3.25</sub> La <sub>0.75</sub> Ti <sub>3</sub> O <sub>12</sub> films with enhanced (011) orientation. <i>Journal of the European Ceramic Society</i> , 2009, 29, 1977-1985.	5.7	5
50	Small scale mechanical properties of polycrystalline materials: in situ diffraction studies. <i>International Journal of Nanotechnology</i> , 2008, 5, 609.	0.2	4
51	Investigation of chalcopyrite film growth at various temperatures: analyses from top to the bottom of the thin films. <i>Journal of Materials Science: Materials in Electronics</i> , 2014, 25, 2237-2243.	2.2	3
52	Thin films of binary amorphous Zn-Zr alloys developed by magnetron co-sputtering for the production of degradable coronary stents: A preliminary study. <i>Bioactive Materials</i> , 2018, 3, 385-388.	15.6	3
53	TWO STEP REACTIVE MAGNETRON SPUTTERING OF BLT THIN FILMS. <i>Integrated Ferroelectrics</i> , 2007, 94, 94-104.	0.7	2
54	Electrical Characteristics of TiTaO Thin Films Deposited on SiO <sub>2</sub> /Si Substrates by Magnetron Sputtering. <i>ECS Solid State Letters</i> , 2013, 2, Q13-Q15.	1.4	2

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55	(Invited) Control of Resistive Switching in Mott Memories Based on TiN/AM4Q8/TiN MIM Devices. ECS Transactions, 2017, 75, 3-12.	0.5	2
56	Control of stoichiometry and morphology in polycrystalline V2O3 thin films using oxygen buffers. Journal of Materials Science, 2020, 55, 14717-14727.	3.7	2
57	An Artificial Neuron Founded on Resistive Switching of Mott Insulators. , 2017, , .		1
58	Mott Memory Devices Based on the Mott Insulator (V1-xCr <sub>x</sub> )2O3. , 2018, , .		1
59	Sol-gel-deposited Sb-doped SnO <sub>2</sub> as transparent anode for OLED: process, patterning, and hole injection characteristics. , 2002, 4464, 103.		0
60	Comparison of Electrical Behavior of GaN-Based MOS Structures Obtained by Different PECVD Process. Materials Science Forum, 0, 711, 228-232.	0.3	0
61	From Resistive Switching Mechanisms in AM4Q8 Mott Insulators to Mott Memories. , 2015, , .		0